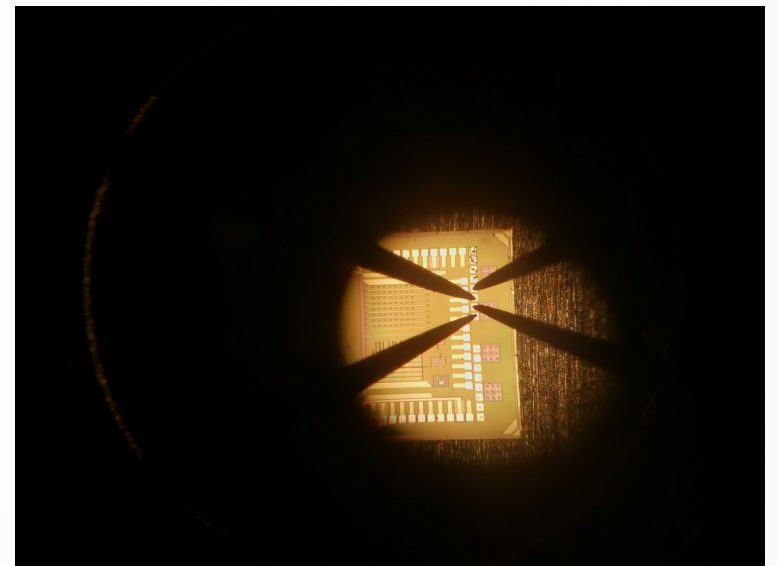
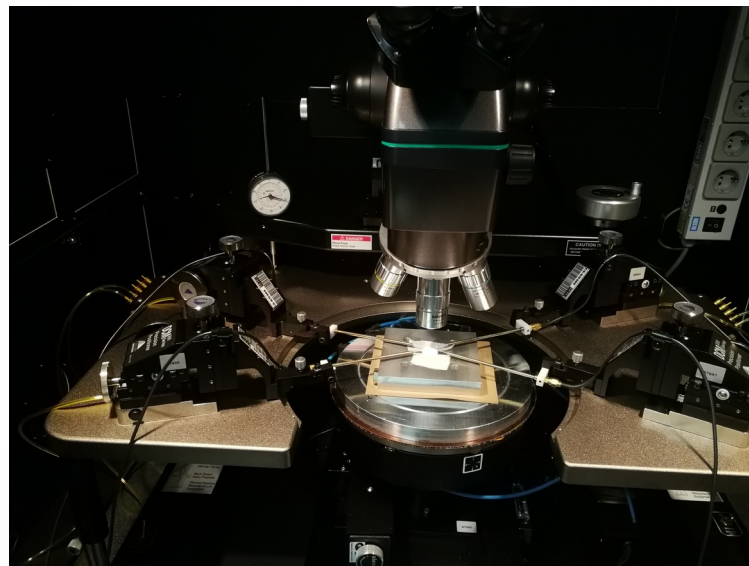
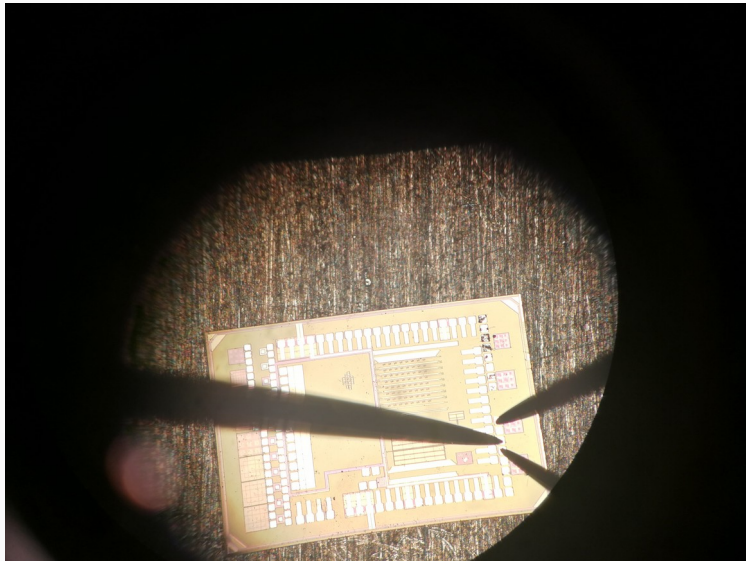


RD50-MPW2 I-V Measurements on test matrices at IFIC

*Ana Catalán Benavent
Ricardo Marco Hernández
IFIC (CSIC-UV)*

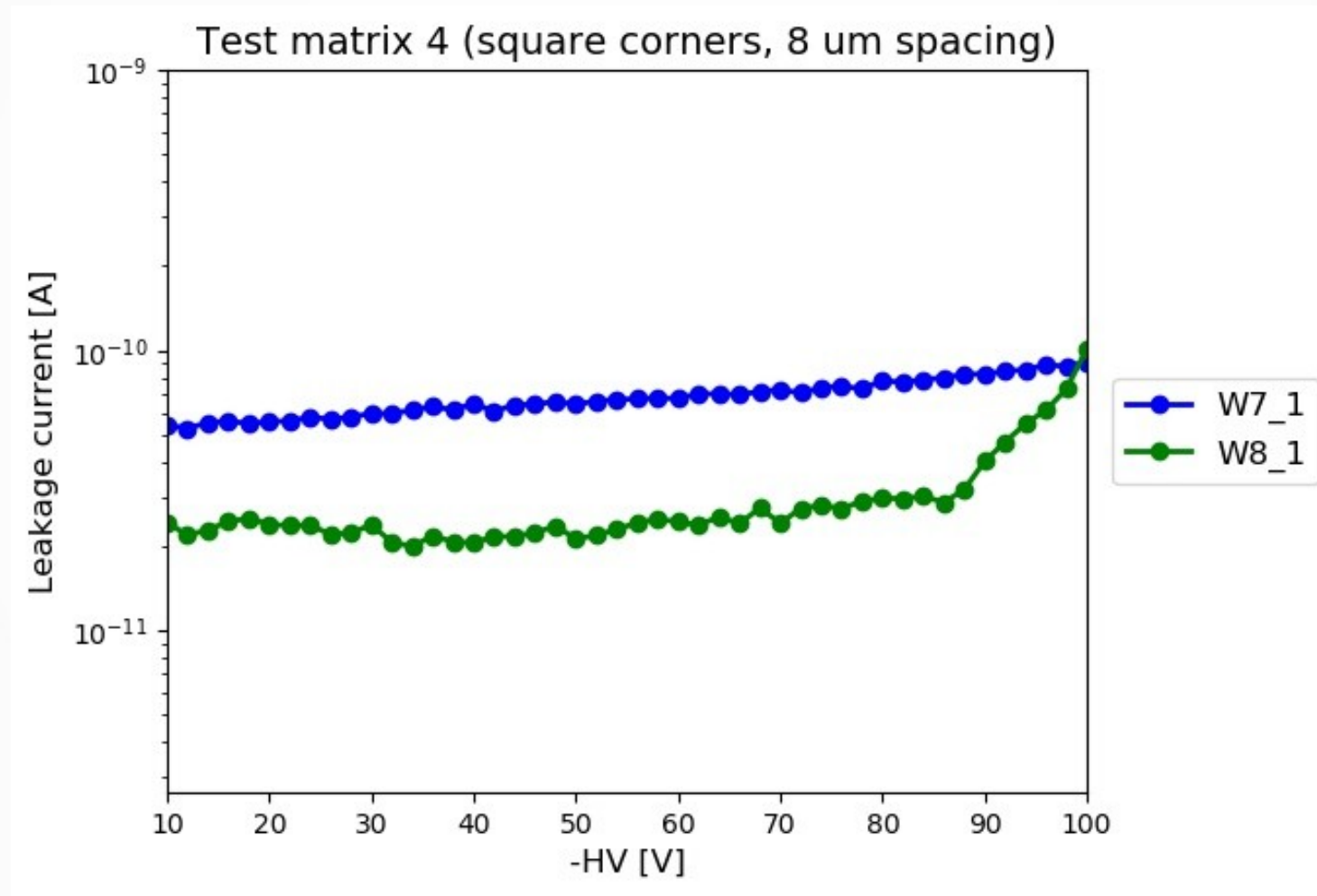
RD50-MPW2 I-V measurements: setup

- Measured I-V on test matrices of MPW2.
- W7, W8, W10, W11, W13 and W14 devices measured.
- All test matrices measured.
- Matrix central pixel measured (pixel HV return pad and GND pad connected together at source GND, HV pad connected to source HV) (W7, W10, W13 → 1st, 2nd and 3rd chips).
- Other configuration used: 8 surrounding pixels connected to GND (W7, W13 → 4th chip and W8, W11, W14).
- Keithley 237 source meter used: different current compliance/measurement range used to be able to measure breakdown voltage.



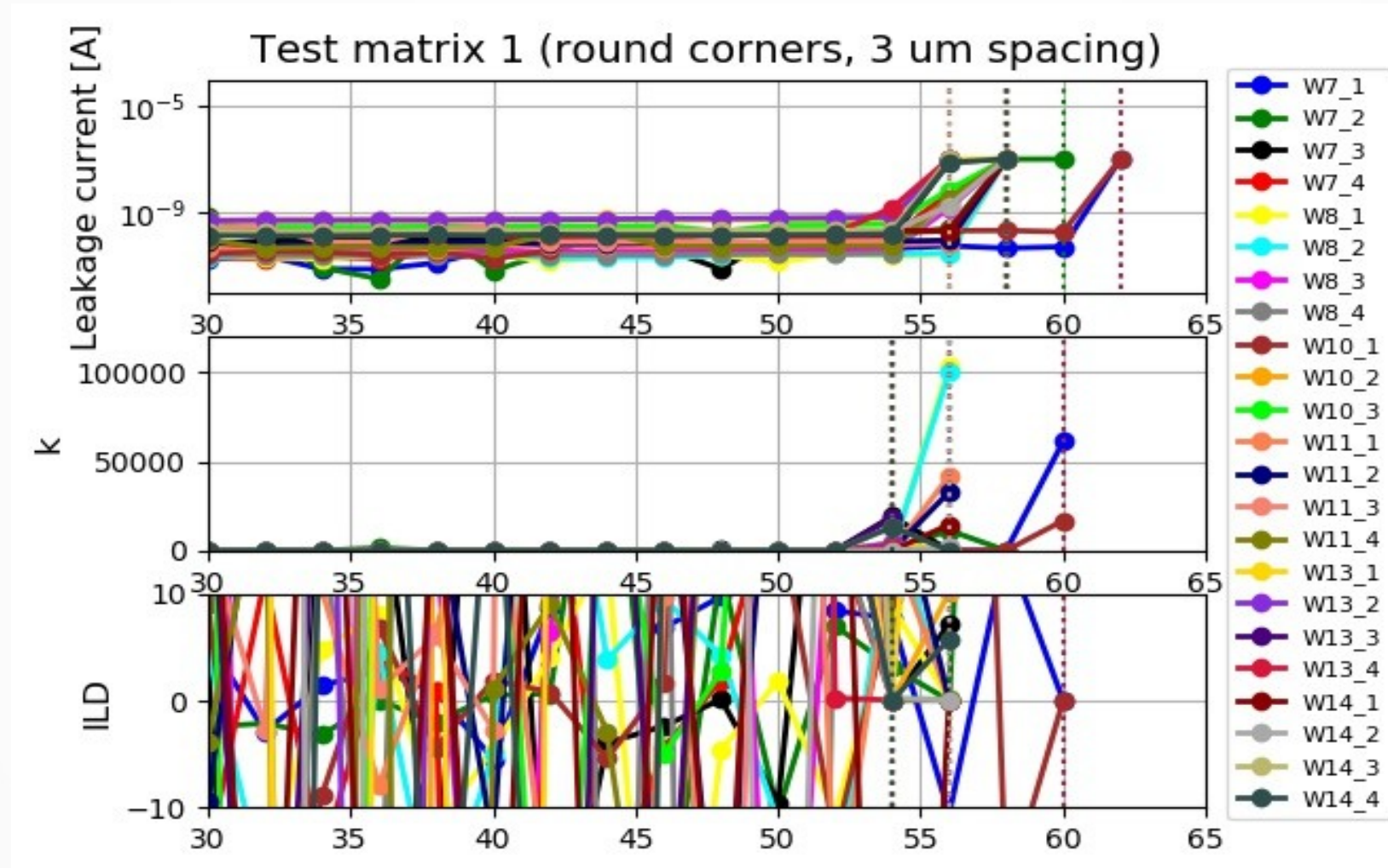
RD50-MPW2 I-V measurements

- Measurements of the leakage current.
- W7_1 → 3 needles set-up.
- W8_1 → 4 needles set-up.



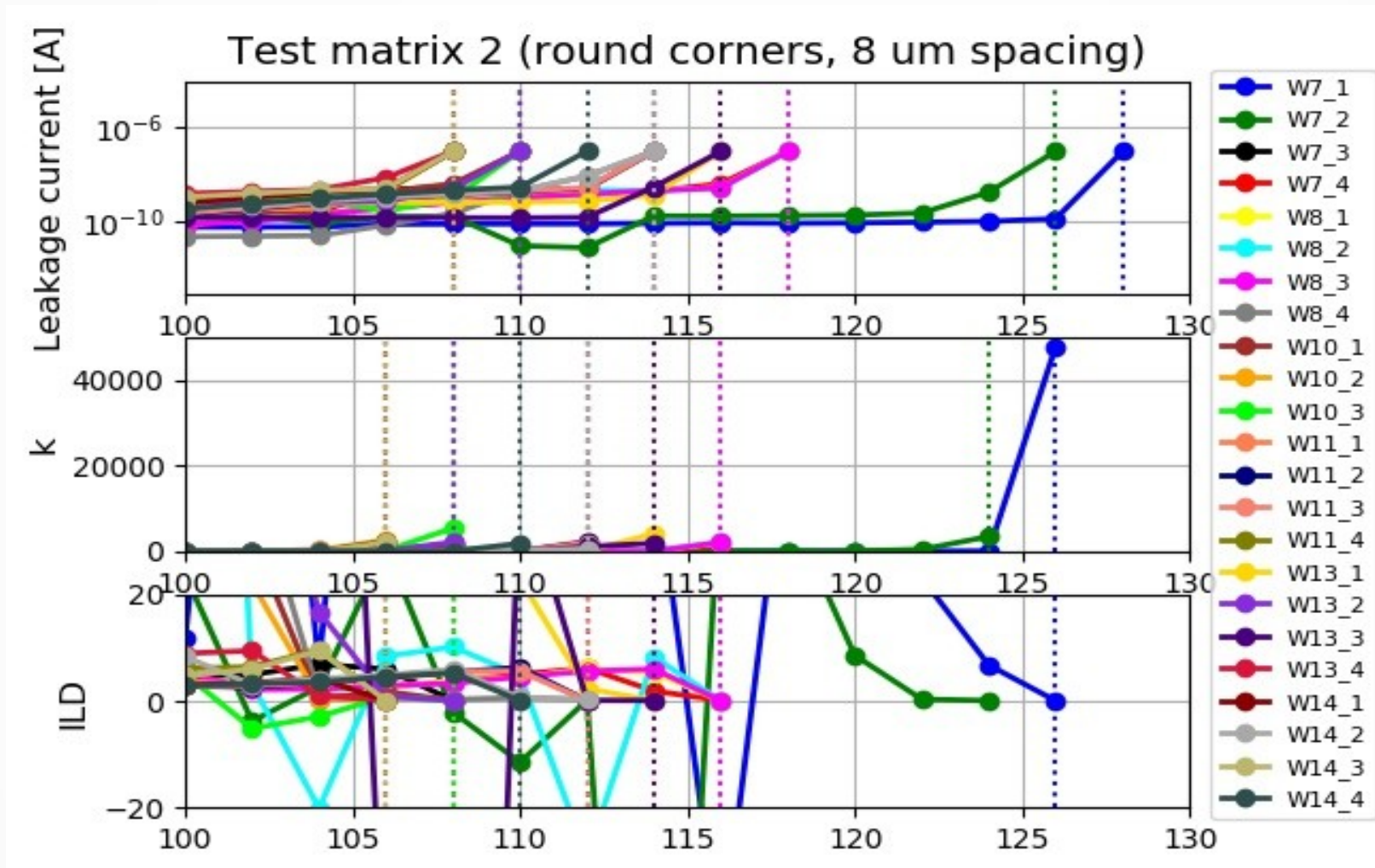
RD50-MPW2 I-V measurements

- First matrix: 3 μm spacing/round corners.
- W7, W8 (0.5-1.1 $\text{k}\Omega\cdot\text{cmcm}$), W10, W11 (1.9 $\text{k}\Omega\cdot\text{cmcm}$) and W13, W14 ($> 2 \text{ k}\Omega\cdot\text{cmcm}$) devices.
- Source current compliance 100 nA.
- Vertical lines pointing to $V(I_{\text{comp}})$, $V(k_{\text{max}})$ and $V(I_{\text{LDmin}} > 0)$ in each plot.



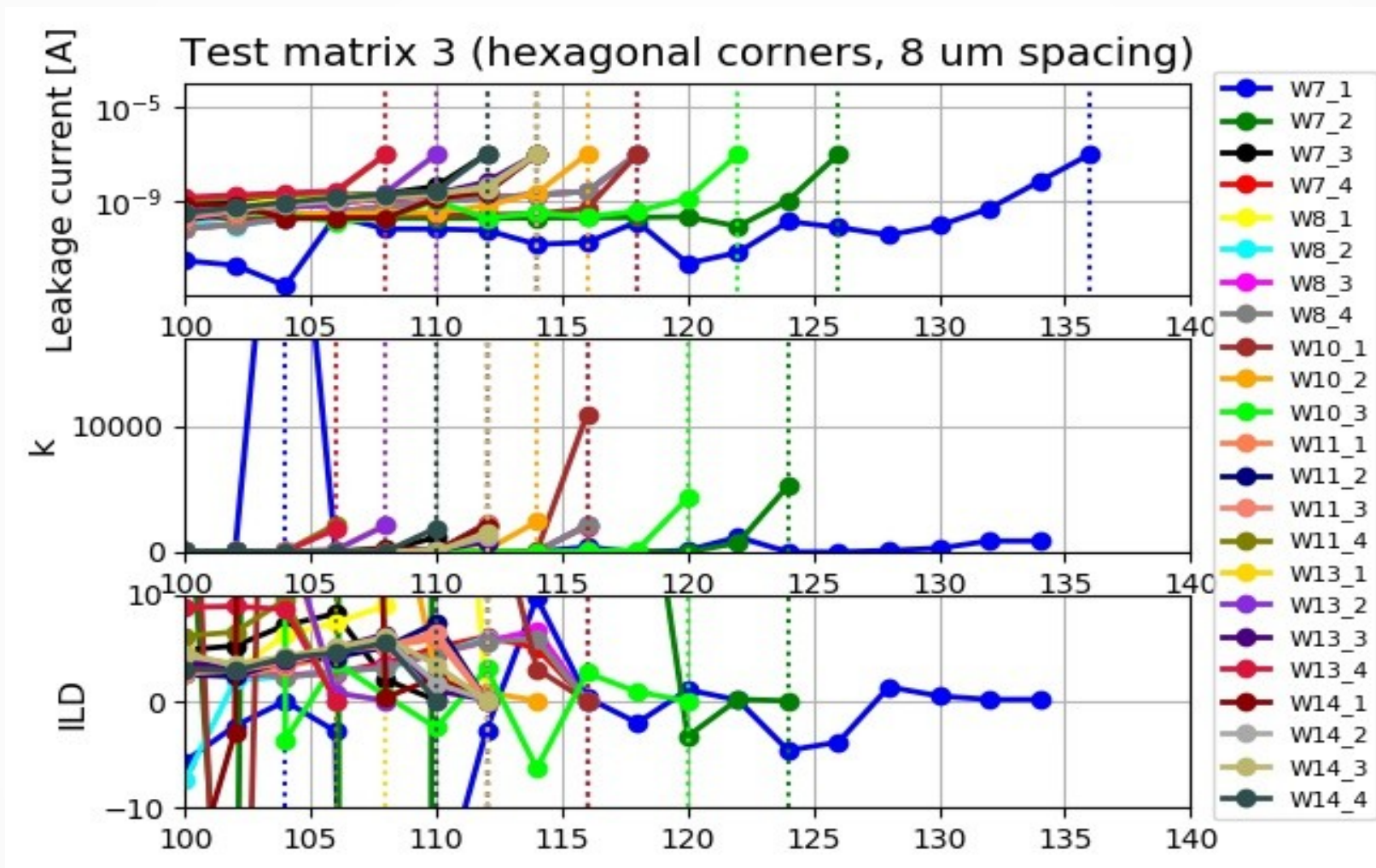
RD50-MPW2 I-V measurements

- Second matrix: 8 μm spacing/round corners.
- W7, W8 (0.5-1.1 $\text{k}\Omega\cdot\text{cmcm}$), W10, W11 (1.9 $\text{k}\Omega\cdot\text{cmcm}$) and W13, W14 ($> 2 \text{ k}\Omega\cdot\text{cmcm}$) devices.
- Source current compliance 10 nA.
- Vertical lines pointing to $V(I_{\text{comp}})$, $V(k_{\text{max}})$ and $V(\text{ILDmin} > 0)$ in each plot.



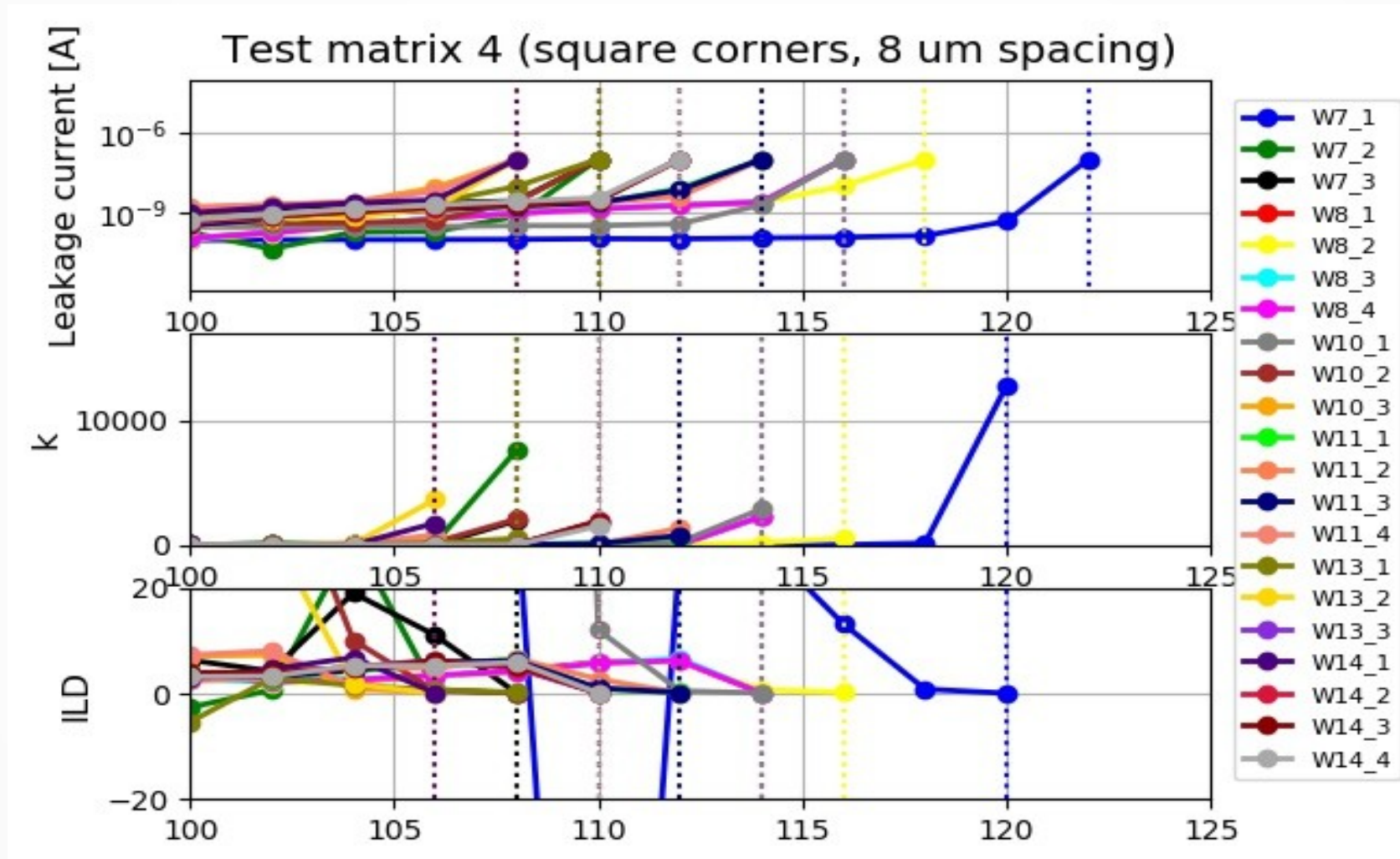
RD50-MPW2 I-V measurements

- Third matrix: 8 μm spacing/hexagonal corners.
- W7, W8 (0.5-1.1 $\text{k}\Omega\cdot\text{cmcm}$), W10, W11 (1.9 $\text{k}\Omega\cdot\text{cmcm}$) and W13, W14 ($> 2 \text{ k}\Omega\cdot\text{cmcm}$) devices.
- Source current compliance 100 nA.
- Vertical lines pointing to $V(I_{\text{comp}})$, $V(k_{\text{max}})$ and $V(\text{ILDmin} > 0)$ in each plot.



RD50-MPW2 I-V measurements

- Fourth matrix: 8 μm spacing/square corners.
- W7, W8 (0.5-1.1 $\text{k}\Omega\cdot\text{cmcm}$), W10, W11 (1.9 $\text{k}\Omega\cdot\text{cmcm}$) and W13, W14 ($> 2 \text{ k}\Omega\cdot\text{cmcm}$) devices.
- Source current compliance 100 nA, 1 μA and 10 μA .
- Vertical lines pointing to $V(I_{\text{comp}})$, $V(k_{\text{max}})$ and $V(I_{\text{LDmin}} > 0)$ in each plot.



RD50-MPW2 I-V measurements: summary

	1st matrix (round 3 μm)			2nd matrix (round 8 μm)			3rd matrix (hexagonal 8 μm)			4th matrix (square 8 μm)		
	Vbd (Icomp)	Vbd (k)	Vbd (ILD)	Vbd (Icomp)	Vbd (k)	Vbd (ILD)	Vbd (Icomp)	Vbd (k)	Vbd (ILD)	Vbd (Icomp)	Vbd (k)	Vbd (ILD)
0.5-1.1 $\text{k}\Omega\cdot\text{cm}$	W7_1 (Icomp = 100nA)			W7_1 (Icomp = 100nA)			W7_1 (Icomp = 100nA)			W7_1 (Icomp = 100nA)		
	62 V	60 V	60 V	128 V	126 V	126 V	126 V	124 V	124 V	122 V	120 V	120 V
	W7_2 (Icomp = 100nA)			W7_2 (Icomp = 1μA)			W7_2 (Icomp = 1μA)			W7_2 (Icomp = 1μA)		
	60 V	56 V	56 V	126 V	124 V	124 V	126 V	124 V	124 V	128 V	126 V	126 V
	W7_3 (Icomp = 100nA)			W7_3 (Icomp = 1μA)			W7_3 (Icomp = 1μA)			W7_3 (Icomp = 1μA)		
	58V	54V	54V	124 V	122 V	122 V	124 V	122 V	122 V	124 V	120 V	120 V
	W7_4 (Icomp = 100nA)			W7_4 (Icomp = 10nA)			W7_4 (Icomp = 10nA)			W7_4 (Icomp = 10nA)		
	56 V	54 V	54 V	124 V	124 V	126 V	122 V	120 V	120 V	120 V	118 V	118 V
	W8_1 (Icomp = 100nA)			W8_1 (Icomp = 100nA)			W8_1 (Icomp = 100nA)			W8_1 (Icomp = 100nA)		
	56 V	54 V	54 V	116 V	114 V	114 V	116 V	114 V	114 V	114 V	114 V	114 V
	W8_2 (Icomp = 100nA)			W8_2 (Icomp = 100nA)			W8_2 (Icomp = 100nA)			W8_2 (Icomp = 100nA)		
	56 V	56 V	56 V	116 V	114 V	116 V	116 V	114 V	114 V	114 V	112 V	112 V
	W8_3 (Icomp = 100nA)			W8_3 (Icomp = 100nA)			W8_3 (Icomp = 100nA)			W8_3 (Icomp = 100nA)		
	56 V	54 V	54 V	116 V	114 V	112 V	116 V	116 V	116 V	112 V	112 V	112 V
	W8_4 (Icomp = 100nA)			W8_4 (Icomp = 100nA)			W8_4 (Icomp = 100nA)			W8_4 (Icomp = 100nA)		
	56 V	54 V	54 V	116 V	114 V	114 V	116 V	114 V	114 V	114 V	112 V	112 V

RD50-MPW2 I-V measurements: summary

	1st matrix (round 3 μm)			2nd matrix (round 8 μm)			3rd matrix (hexagonal 8 μm)			4th matrix (square 8 μm)		
1.9 $\text{k}\Omega\cdot\text{cm}$	W10_1 (Icomp = 100nA)			W10_1 (Icomp = 100nA)			W10_1 (Icomp = 100nA)			W10_1 (Icomp = 100nA)		
	62 V	60 V	60 V	120 V	118 V	118 V	118 V	116 V	116 V	116 V	114 V	114 V
	W10_2 (Icomp = 100nA)			W10_2 (Icomp = 10μA)			W10_2 (Icomp = 1μA)			W10_2 (Icomp = 1μA)		
	58 V	54 V	54 V	124 V	122 V	122 V	126 V	124 V	124 V	122 V	118 V	118 V
	W10_3 (Icomp = 100nA)			W10_3 (Icomp = 1μA)			W10_3 (Icomp = 1μA)			W10_3 (Icomp = 1μA)		
	58 V	54 V	54 V	124 V	122 V	122 V	120 V	118 V	118 V	118 V	116 V	116 V
	W11_1 (Icomp = 100nA)			W11_1 (Icomp = 10nA)			W11_1 (Icomp = 10nA)			W11_1 (Icomp = 10nA)		
	56 V	54 V	54 V	112 V	110 V	110 V	122 V	122 V	120 V	112 V	112 V	110 V
	W11_2 (Icomp = 100nA)			W11_2 (Icomp = 10nA)			W11_2 (Icomp = 10nA)			W11_2 (Icomp = 10nA)		
	56 V	54 V	54 V	112 V	110 V	110 V	122 V	120 V	120 V	112 V	110 V	110 V
	W11_3 (Icomp = 100nA)			W11_3 (Icomp = 10nA)			W11_3 (Icomp = 10nA)			W11_3 (Icomp = 10nA)		
	56 V	54 V	54 V	112 V	110 V	110 V	122 V	120 V	120 V	112 V	110 V	110 V
	W11_4 (Icomp = 100nA)			W11_4 (Icomp = 10nA)			W11_4 (Icomp = 10nA)			W11_4 (Icomp = 10nA)		
	56 V	54 V	54 V	110 V	108 V	108 V	116 V	114 V	114 V	116 V	114 V	114 V
>2 $\text{k}\Omega\cdot\text{cm}$	W13_1 (Icomp = 100nA)			W13_1 (Icomp = 100nA)			W13_1 (Icomp = 100nA)			W13_1 (Icomp = 100nA)		
	58 V	54 V	54 V	118 V	116 V	116 V	120 V	118 V	118 V	120 V	118 V	118 V
	W13_2 (Icomp = 100nA)			W13_2 (Icomp = 10μA)			W13_2 (Icomp = 10μA)			W13_2 (Icomp = 10μA)		
	56 V	54 V	54 V	124 V	122 V	122 V	122 V	120 V	120 V	120 V	118 V	118 V
	W13_3 (Icomp = 100nA)			W13_3 (Icomp = 100nA)			W13_3 (Icomp = 100nA)			W13_3 (Icomp = 100nA)		
	54 V	52 V	52 V	124 V	122 V	122 V	122 V	122 V	120 V	118 V	116 V	116 V

RD50-MPW2 I-V measurements: summary

	1st matrix (round 3 μm)			2nd matrix (round 8 μm)			3rd matrix (hexagonal 8 μm)			4th matrix (square 8 μm)		
	W13_4 (Icomp = 100nA)			W13_4 (Icomp = 10nA)			W13_4 (Icomp = 10nA)			W13_4 (Icomp = 10nA)		
	54 V	52 V	52 V	116 V	114 V	114 V	116 V	114 V	114 V	116 V	114 V	114 V
	W14_1 (Icomp = 100nA)			W14_1 (Icomp = 10nA)			W14_1 (Icomp = 10nA)			W14_1 (Icomp = 10nA)		
	56 V	54 V	54 V	116 V	114 V	114 V	122 V	120 V	118 V	110 V	108 V	108 V
	W14_2 (Icomp = 100nA)			W14_2 (Icomp = 10nA)			W14_2 (Icomp = 10nA)			W14_2 (Icomp = 10nA)		
	54 V	54 V	56 V	122 V	120 V	120 V	122 V	120 V	120 V	108 V	108 V	106 V
	W14_3 (Icomp = 100nA)			W14_3 (Icomp = 10nA)			W14_3 (Icomp = 10nA)			W14_3 (Icomp = 10nA)		
	52 V	52 V	54 V	116 V	114 V	114 V	122 V	120 V	120 V	110 V	108 V	108 V
	W14_4 (Icomp = 100nA)			W14_4 (Icomp = 10nA)			W14_4 (Icomp = 10nA)			W14_4 (Icomp = 10nA)		
	54 V	54 V	56 V	120 V	118 V	118 V	120 V	122 V	118 V	110 V	108 V	108 V

Next Steps

- C-V measurements of different test matrices of MPW2 for three resistivities.
- I-V measurements of the irradiated test matrices.